8th IEEE North Atlantic Test Workshop

"Reliability and Testing Issues for the 21st Century"

URI W. Alton Jones Campus
West Greenwich, RI
May 27-28, 1999

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Call For Papers

The IEEE North Atlantic Test Workshop provides a forum for discussions on the latest issues relating to high quality, more economical, and more efficient testing methodologies and designs. The 8th workshop will again forcus on *"Reliability and Testing Issues for the 21st Century"*. The major topics include, but are not limited to, the following:

- **Analog Circuit Testing**
- **Automatic Test Generation**
- **Built-In Self Test (BIST)**
- **Card/Board Testing**
- **Delay Testing**
- **Design for Testability**
- **Design Verification**
- **Economies of Test**
- **Embedded Core Testing**
- **Fault Modeling and Diagnostics**
- **Fault Simulation**
- **Hierarchical Test Generation**
- **High Frequency Test**
- **IDDQ Testing**
- **MCM Testing**
- **Mixed Signal Test**
- **Reliability**
- **Online Testing**
- **Self-Checking Circuits**
- **Synthesis for Testability**
- **System Testing**
- **Testing Philosophies**

The Program Committee invites authors to submit original, unpublished paper and panel proposals. Papers may be extended summaries or full papers. Clearly describe the nature of the work, explain its significance, highlight novel features, and its current status. On the title page, please indicate: the title, names and affiliations of all authors, an abstract of 50 words, and the suggested topics. Also, identify a contact author and include a complete mailing address, phone and fax numbers and E-mail address. For hard copy submissions, please send **3** copies of paper proposal to the Program Chair. For electronic submissions, the papers should be prepared in either Postscript or PDF format and should be submitted to the NATW'99 ftp site at **ftp://ele.uri.edu/incoming/natw99**. Please use binary mode transfer to ensure the file integrity. An email must be sent to the Program Chair regarding the submission. Submissions are due no later than **2/1/99**. Camera-ready papers for inclusion in the proceedings must be received by **4/15/99**.

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To view this call-for-papers online and see other information regarding this workshop, visit our home page at **http://www.ele.uri.edu/natw99**.

The 1999 North Atlantic Test Workshop is sponsored by the **IEEE Computer Society Test Technology Technical Committee** and the **University of Rhode Island**.